

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF: :

HIDEAKI YOSHIDA ET AL. : NEW APPLICATION DIVISION

SERIAL NO: NEW APPLICATION :

FILED: HEREWITH :

FOR: CONTACT PROBE AND PROBE
DEVICE

#5
Pay/amt - A
4/19/83
T.B

PRELIMINARY AMENDMENT

ASSISTANT COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

SIR:

Prior to a further examination on the merits, please amend the above-identified application as follows:

IN THE CLAIMS

Please cancel Claims 2-11 and 14-20 without prejudice:

Please amend Claims 1 and 12 as follows:

1. (Amended) In a probe device, an improved contact probe comprising:
 - a film;
 - a plurality of wiring patterns formed on a first surface of the film, each wiring pattern having a front end portion projecting out from the first surface of the film in a direction parallel to the first surface of the film so as to form contact pins; and
 - a metal layer provided on a second surface of the film,
 - wherein the plurality of contact pins include a fabricated bending point at a middle portion in an axial line direction with a Ni plating treatment.

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